



CHARACTERIATION, TESTING, AND QUALITY CONTROL OF NANOTECHNOLOGY-BASED PRODUCTS:

THE PHILIPPINES' CAPABILITIES

by

Blessie A. Basilia, PhD

Industrial Technology Development Institute, Department of
Science and Technology

Bicutan, Taguig City, Metro Manila, Philippines 1631

basiliablessie@gmail.com, msd@itdi.dost.gov.ph

Some Nanotechnology R&D in the Philippines

BULACAN

- **Nanotechnology Application**
 - *Environment*
 - . nanosensors

- **Synthesis of nanomaterials**
 - Carbon nanofibers
- **Nanocomposites**
 - Natural rubber nanoclay
- **Nanotechnology Application**
 - *ICT and Semis-conductors*
 - . Aluminum carbon nanotube for heat sinks in microprocessors
 - . Nanotungsten carbide as tooling for IC fabrication
 - . Lead-free solder paste with carbon nanotube for IC packaging
 - . CNT doped boron nitride nanotube for optical light source
 - . Epoxy multiwalled carbon nanotube for IC encapsulation
 - *Health and biomedical*
 - . PVA-chitosan nanofibrous membrane for drug delivery

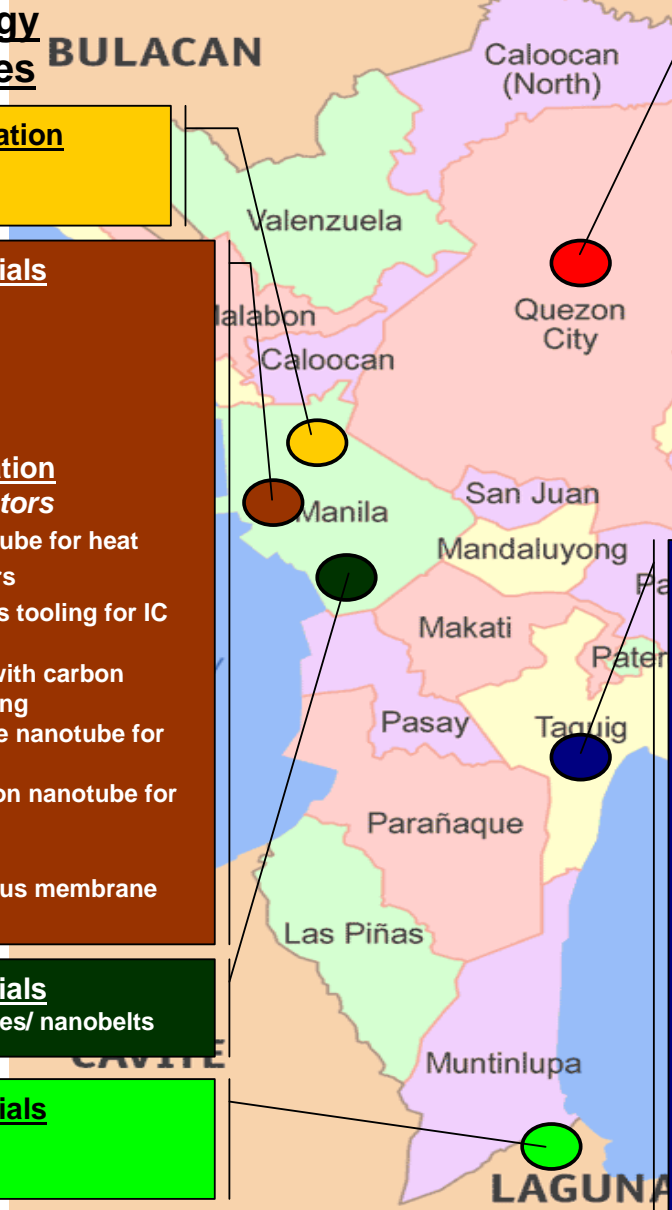
- **Synthesis of nanomaterials**
 - SnO nanocarbons/ nanowires/ nanobelts

- **Synthesis of nanomaterials**
 - ZnO nanowires
 - Polymer nanofibers

- **Synthesis of nanomaterials**
 - ZnO nanowires
 - Polymer nanofibers
 - GaAs nanowires
 - InAs quantum dots
 - Carbon nanofibers

- **Nanotechnology application**
 - *ICT and Semi-conductors*
 - . Thermal interface material with nanoclay for IC packaging
 - . GaAs based quantum well devices for RF application
 - *Health and Biomedical*
 - . Carbon nanotubes for cancer diagnosis detection

- **Synthesis of nanomaterials**
 - Nanoclay
 - Alumina powder
 - Magnetic nanoparticles (Fe)
 - ZnO nanopowder
- **Nanocomposites**
 - Polycarbonate nanoclay
 - Thermoplastic elastomer nanographite
 - PET carbon nanotubes
 - Polycarbonate carbon nanotubes
 - Thermoplastic carbon nanotube nanographite
 - Epoxy halloysite nanotubes
- **Nanotechnology application**
 - *ICT and Semi-conductors*
 - . PCB substrate from recycled polycarbonate and nanoclay
 - *Health and Biomedical*
 - . Nanofibrous membrane for tissue engineering
 - . Load bearing Hap-Alumina biocomposite
 - *Environment*
 - . PMMA-nanoclay nanofibrous membrane for waste treatment
 - . Chitosan biosorbent and membrane for industrial application



- UPD
- UPLB
- MAPUA
- DLSU
- UST
- ITDI-DOST

Some Nanotechnology R&D in the Philippines

NANOTECHNOLOGY

Prospects and Priorities



Edited by:
Fabian M. Dayrit



CHAPTER 1

PROSPECTS AND PRIORITIES OF NANOTECHNOLOGY IN THE PHILIPPINES: AN OVERVIEW

CHAPTER 2

APPLICATIONS OF NANOTECHNOLOGY IN FOOD, AGRICULTURE, AND FORESTRY

CHAPTER 3

NATURAL NANOMATERIALS FOR POLYMERS AND COMPOSITES

CHAPTER 4

APPLICATIONS OF NANOTECHNOLOGY IN ENERGY

CHAPTER 5

PROSPECTS AND PRIORITIES IN NANOMEDICINE

CHAPTER 6

APPLICATIONS OF NANOTECHNOLOGY IN ICT AND SEMICONDUCTORS

CHAPTER 7

APPLICATIONS OF NANOTECHNOLOGY TO THE ENVIRONMENT

CHAPTER 8

SAFETY AND RISK ISSUES IN NANOTECHNOLOGY

CHAPTER 9

EDUCATION AND METROLOGY FOR NANOTECHNOLOGY

CHAPTER 10

SUMMARY AND RECOMMENDATIONS: A NANOTECHNOLOGY ROADMAP FOR THE PHILIPPINES

Advanced Device and Materials Testing Laboratory (ADMATEL)



Office Hours:
8AM – 5PM, Monday - Friday

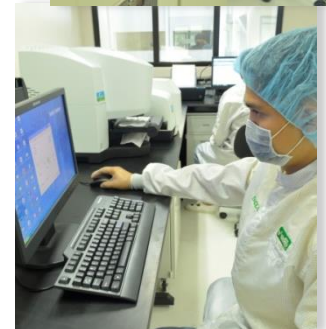
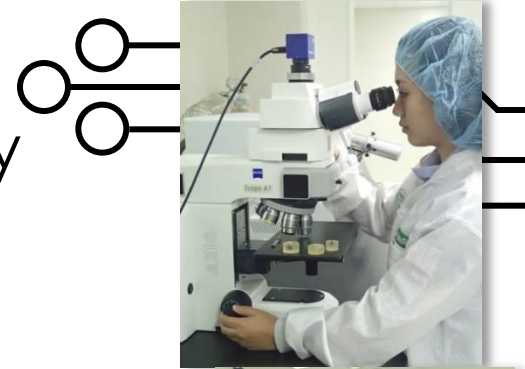
Class 100K Cleanroom Facility
Standard ESD Safety Compliance
ISO 17025 ACCREDITED LABORATORY
ISO 9001:2015 Certified

Advanced Device and Materials Testing Laboratory (ADMATEL)

ADMATEL is a DOST national testing facility equipped with advanced analytical instruments for Failure Analysis and Materials Characterization

IT WAS ESTABLISHED:

- To reinforce/ upgrade FA and Materials Testing Facilities of our local industry
- To provide shorter turn-around time
- To provide less expensive analysis
- To attract potential investors seeking for a more conducive business environment

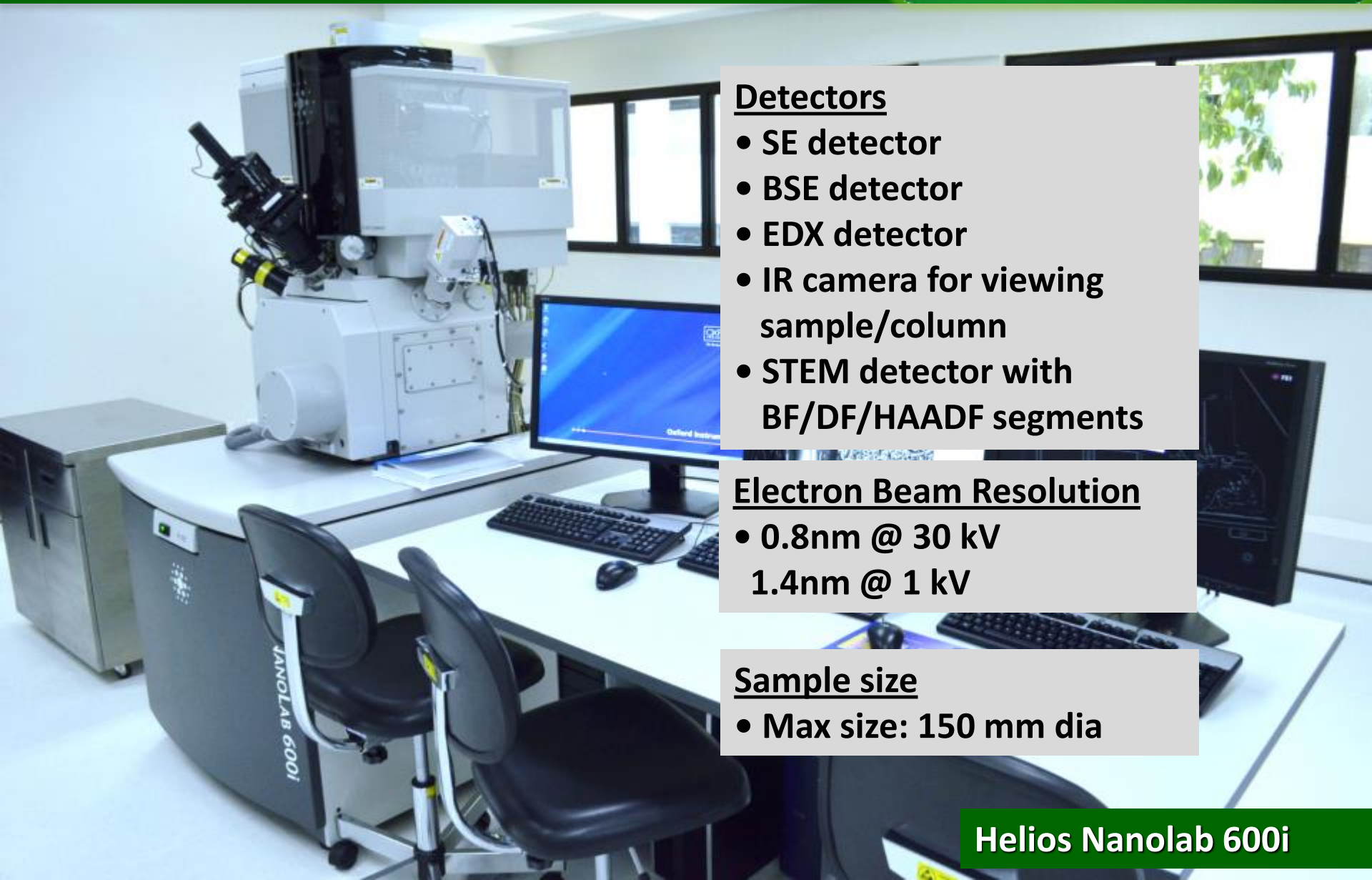


ADMATEL LABORATORIES



**Class 100k clean room laboratories
Standard ESD safety compliance**

FOCUSED ION BEAM (FIB) – FIELD EMISSION SCANNING ELECTRON MICROSCOPE (FESEM)



Detectors

- SE detector
- BSE detector
- EDX detector
- IR camera for viewing sample/column
- STEM detector with BF/DF/HAADF segments

Electron Beam Resolution

- 0.8nm @ 30 kV
- 1.4nm @ 1 kV

Sample size

- Max size: 150 mm dia

Helios Nanolab 600i

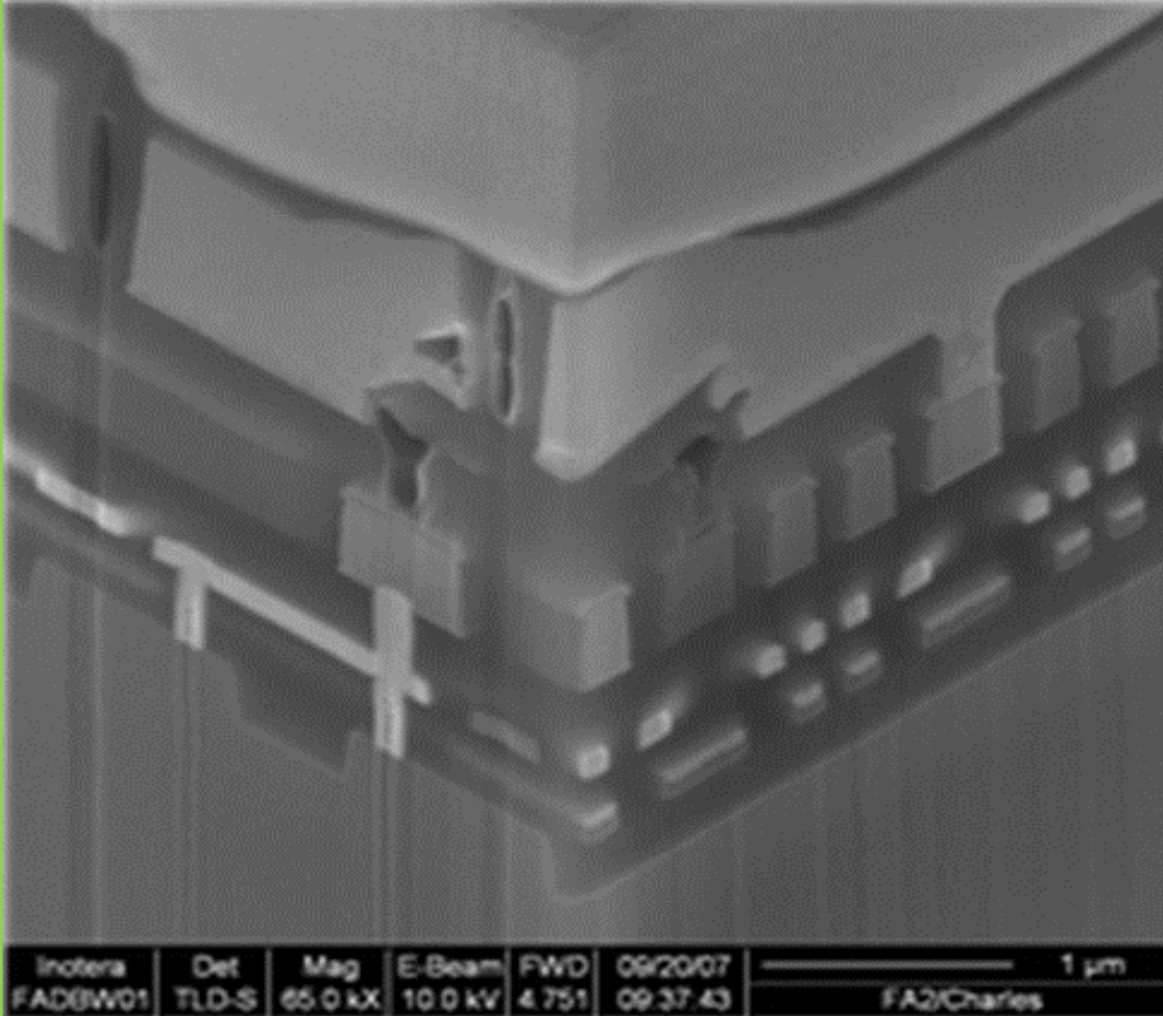
FIB-FESEM SERVICES



- Defect Analysis
- Failure Analysis
- TEM Lamella Preparation
- Metrology at Nano scale
- STEM analysis
- EDS Analysis
- Site Specific Sample Preparation
- Prototyping for MEMS and NEMS

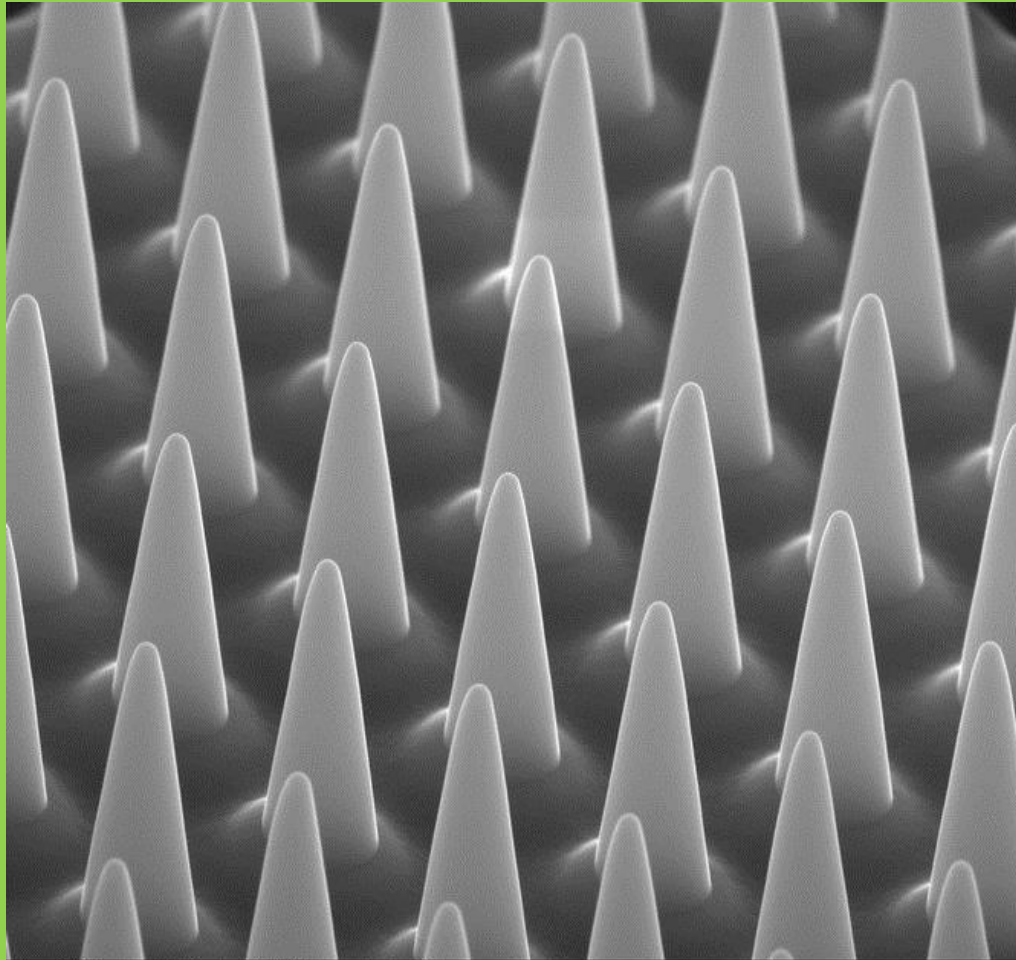


Site Specific Sample Preparation



Bi-directional cross-section through an IC device.

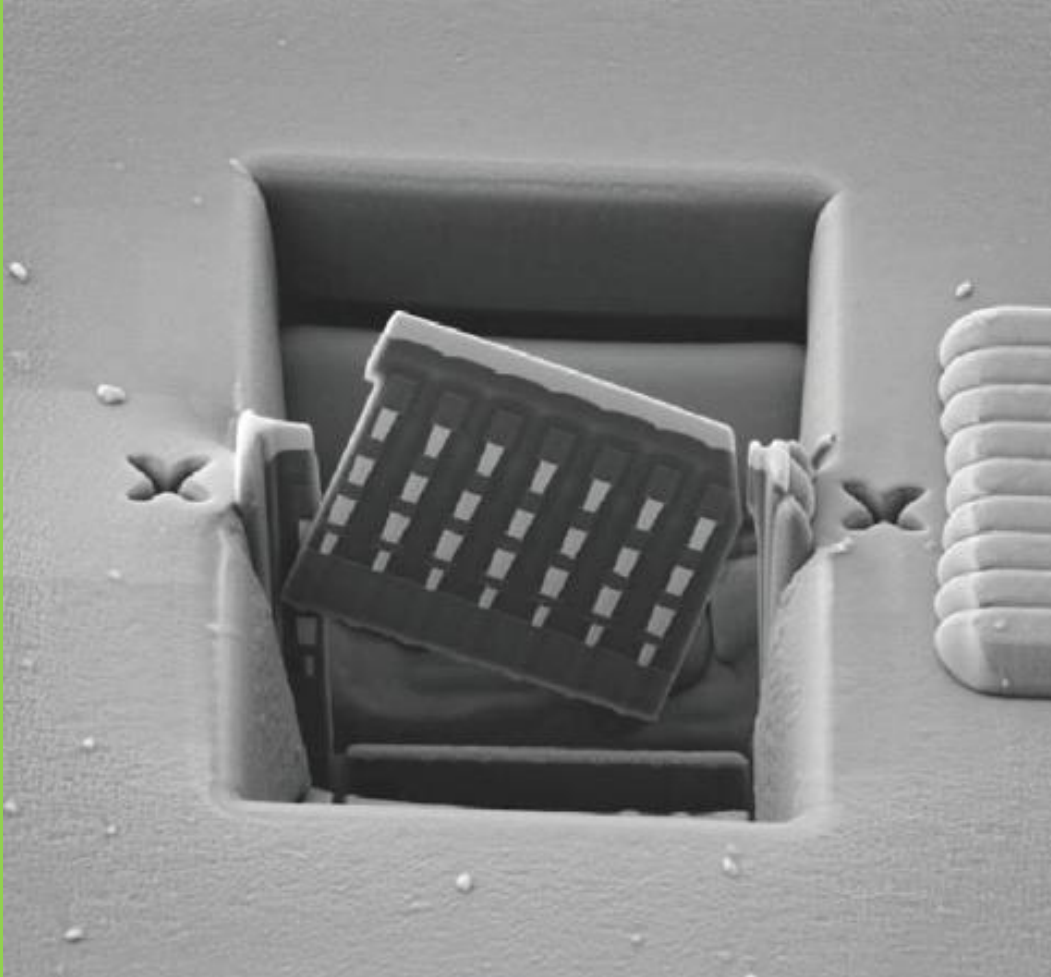
Site Specific Sample Preparation



HV 10.00 kV WD 5.1 mm HFW 4.42 μ m mode SE det TLD57 mag 57 947 x 2 μ m Nova D-0182

- Field emitters formed by focused ion beam milling.
- Diameter of tip - less than 100 nm.

STEM Preparation



- Created with focused ion beam and ready for transfer to TEM grid.

Magnification: 57,947x | Voltage: 10 kV | Detector: SE
Spot: 3.0 nA | Working Distance: 5.1 mm

AUGER ELECTRON SPECTROSCOPE (AES)



Specifications:

- 3 nm SEI resolution
- 8 nm probe diameter for Auger analysis
- Chemical state analysis in several 10 nm areas
- Allows Auger analysis of insulating materials

Max sample size:

- 95 mm in diameter



JEOL JAMP-9500F
Field Emission Auger Microprobe

JAMP-9500F FIELD EMISSION AUGER MICROPROBE (FE-AUGER)

AES TESTING SERVICES



- **Depth profile analysis**
- **Spectrum Measurement**
- **Surface map analysis**
- **Line analysis measurement**
- **Element identification**
- **Insulator material analysis**
- **Elemental microanalysis (≤ 1 atomic percentage)**
- **Imaging of part analysis (max magnification 500k)**



TIME-OF-FLIGHT SECONDARY ION MASS SPECTROMETER (TOF-SIMS)

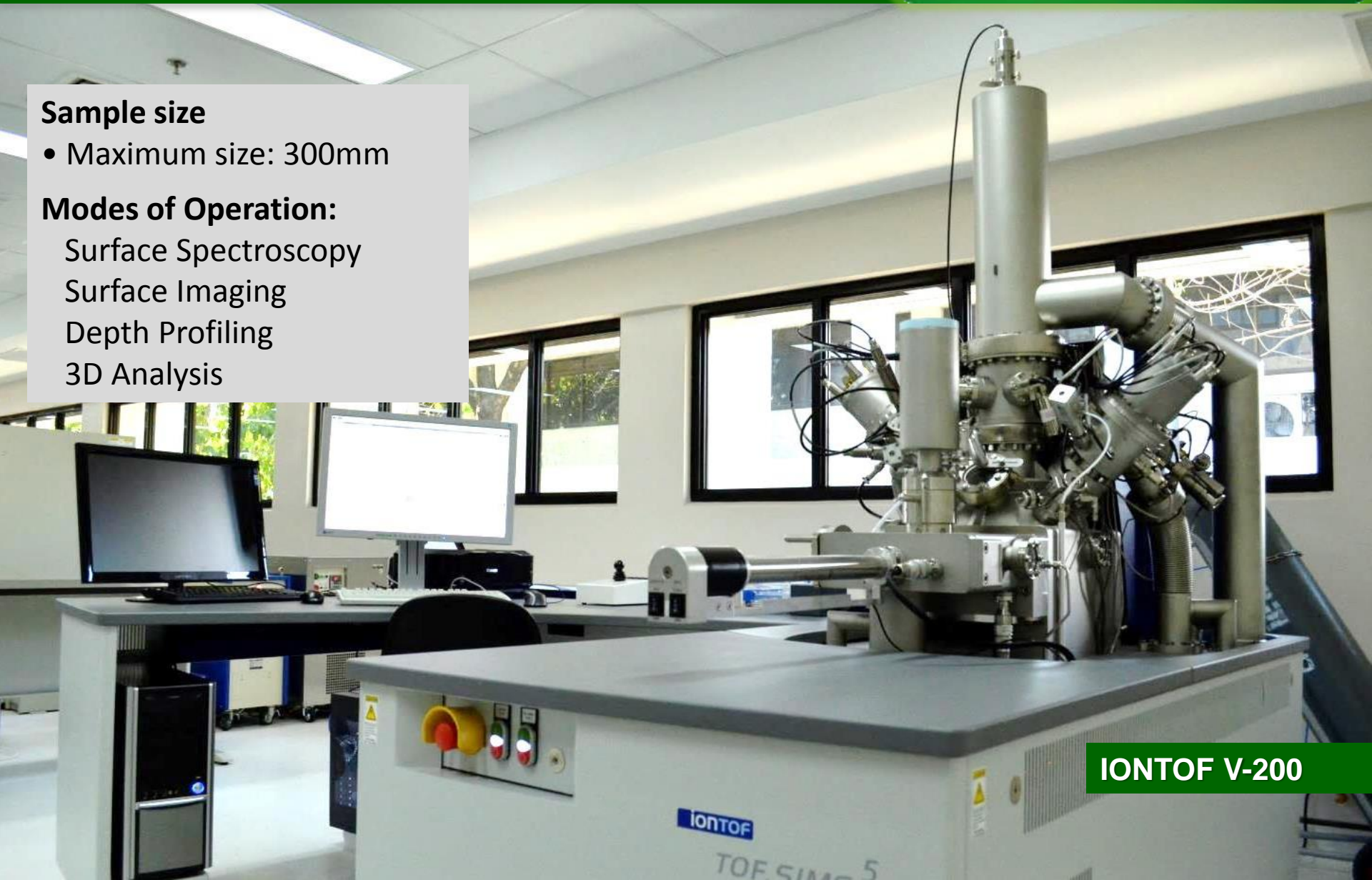


Sample size

- Maximum size: 300mm

Modes of Operation:

- Surface Spectroscopy
- Surface Imaging
- Depth Profiling
- 3D Analysis



IONTOF V-200

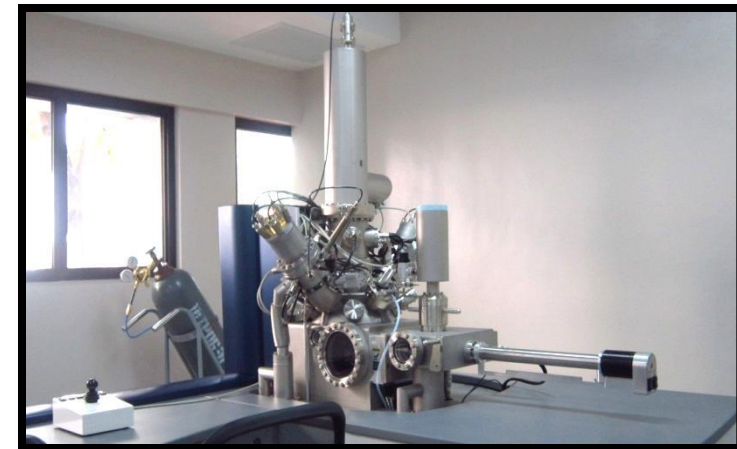
IONTOF

TOF SIMS 5

TOF-SIMS SERVICES



- Trace Metal Detection / Quantification
 - simultaneous detection of all elements (ppm/ppb range)
 - small surface areas (patterned wafers)
 - in depth distribution
 - backside contaminants
- Screening for Contaminants
 - inorganic and organic
 - particle analysis
- Gate Oxide analysis
 - Ultra-thin dielectric layers (Oxinitrides, High-k)
 - nitrogen content, oxide thickness
- Analysis of shallow Implants
 - high sensitivity
 - parallel mass detection (contaminant screening)
- Failure analysis
 - Interface, bond pad, test pad analysis
 - Defect and particle analysis



FTIR SPECTROSCOPY AND IMAGING



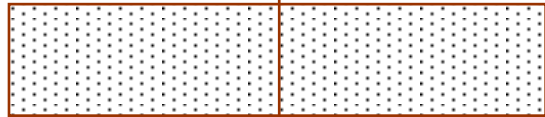
- Failure analysis
- Micro-contamination identification
- Adhesive performance
- Material delamination
- Corrosion chemistry
- Chemical analysis of samples down to about 10 x 10 μm : fibers, particles, crystals
- Analysis of inhomogenieties in a larger matrix
- Surface studies/characterization



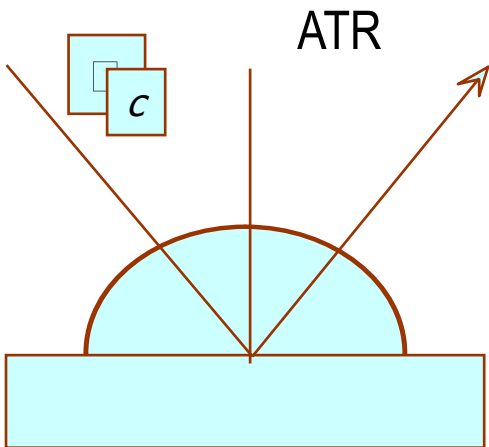
Spectrum Spotlight 200

INFRARED SAMPLING MODES

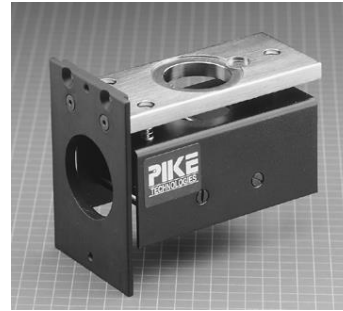
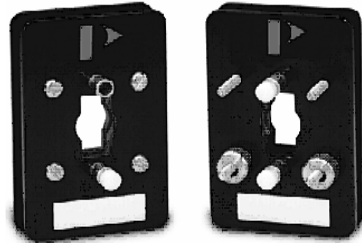
Transmission



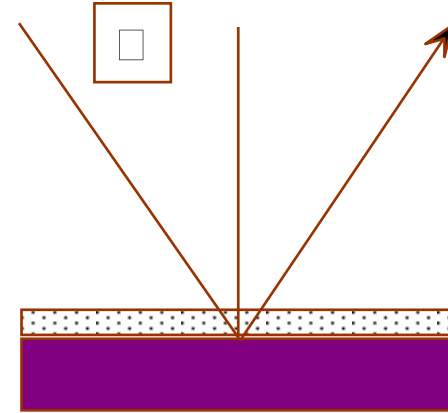
Transmission



Internal reflection



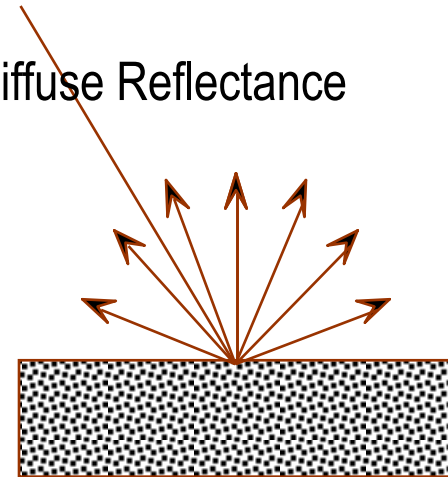
Specular Reflectance



Reflection-absorption



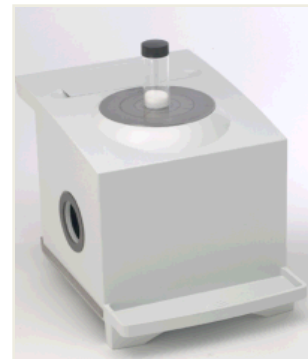
Diffuse Reflectance



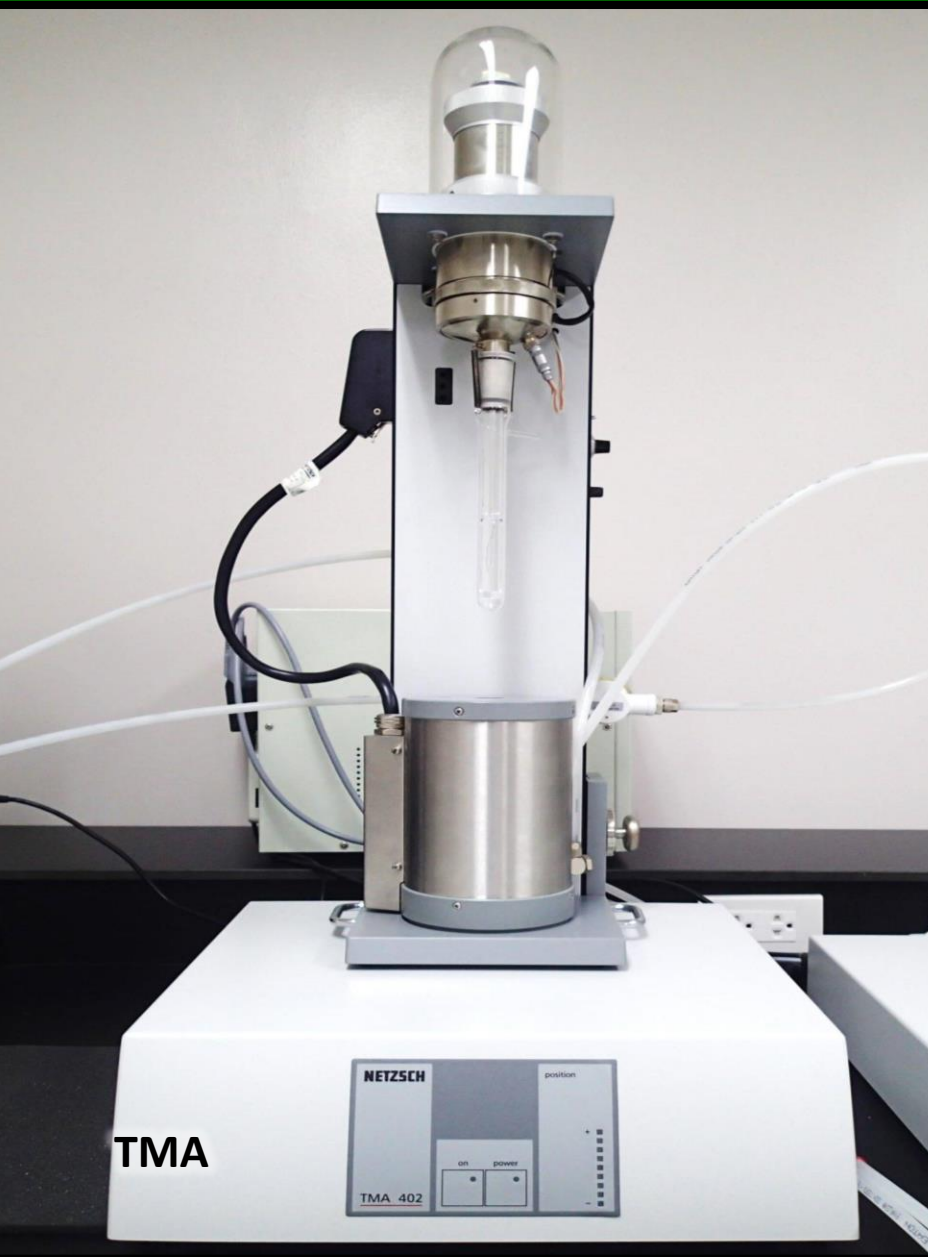
Diffuse reflection



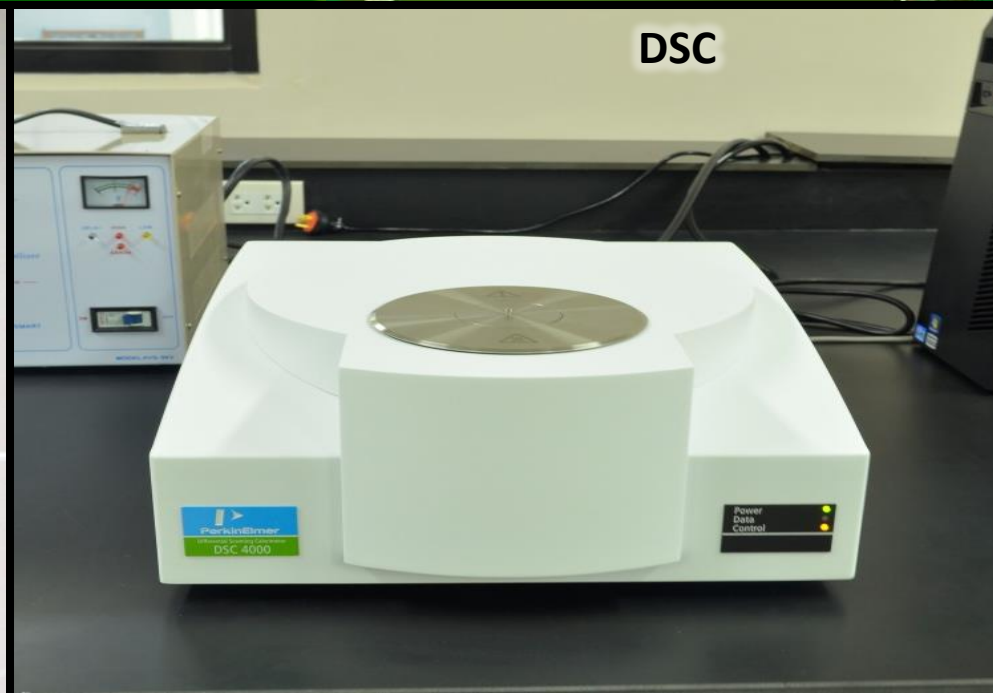
Evacuatable KBr Die



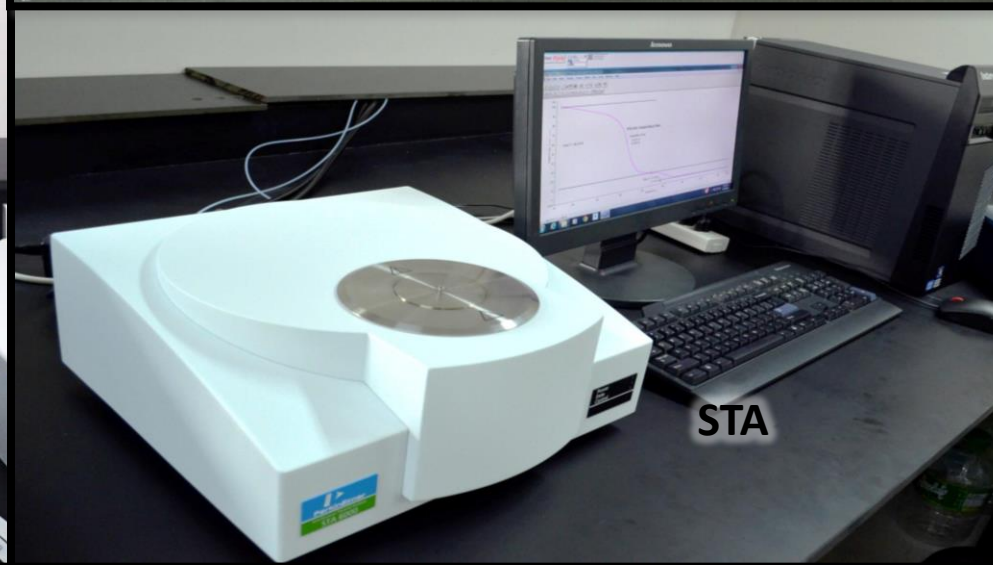
THERMAL ANALYSIS EQUIPMENT



TMA



DSC

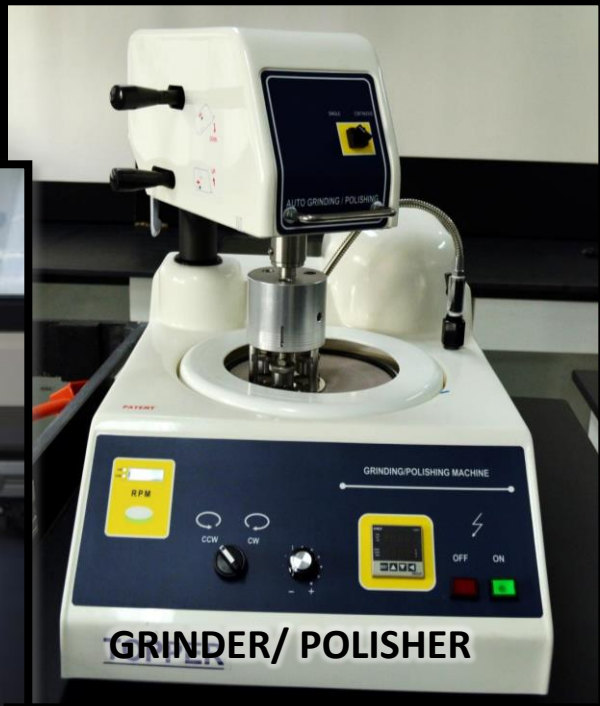


STA

SAMPLE PREPARATION AND EXTERNAL VISUAL INSPECTION



DIAMOND SAW





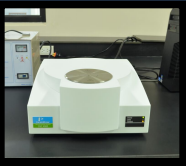

ION CROSS-SECTION POLISHER



OPTICAL MICROSCOPES




TESTING SERVICES



Equipment	Services	Description	Application
TG-DTA and FTIR 	Hyphenated TG-FTIR analysis	Simultaneous analysis of evolved gases and % weight loss during heating.	Compositional Analysis of Materials, Reverse Engineering
Auger Electron Spectroscopy 	Chemical State Analysis	Determines the chemical state of selected elements	Used to verify the composition of oxide layer found in leadframe pads or delaminated interface.
DSC 	Kinetics Study	Thermal analysis study by varying the soak time at constant temperature	Determination of curing time for epoxies.
TMA 	Determination of Coefficient of Thermal Expansion	Measures the dimensional change of sample in one (1) axis during heating	Determination of CTE and Tg for Metals, ceramics, polymers, and composites.

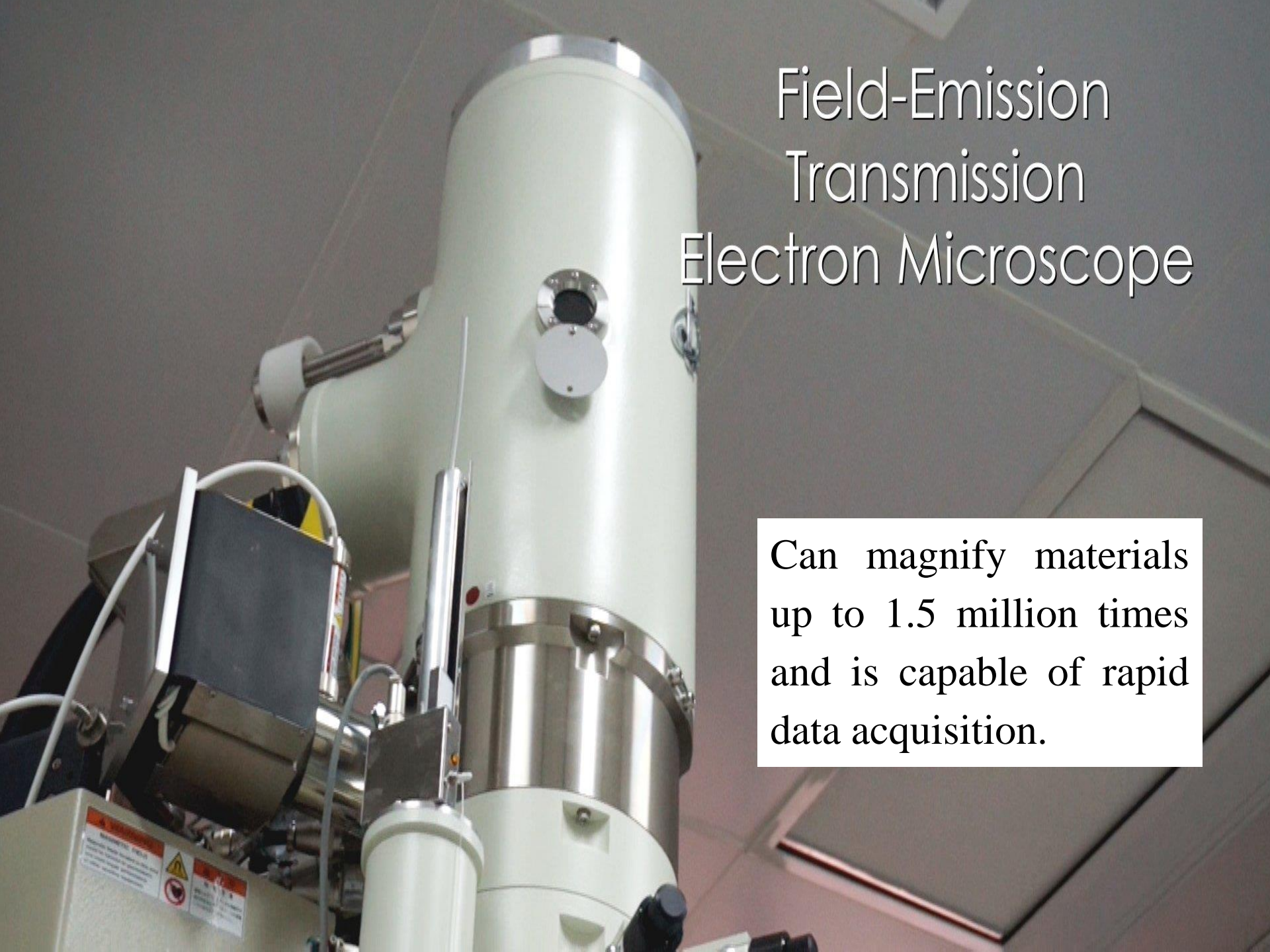
TESTING SERVICES



Eqpt	Services	Description	Application
TMA 	Determination of Glass Transition Temperature	Measures the dimensional change of sample in one (1) axis during heating	Polymeric materials
FIB-FESEM 	STEM Imaging with EDS analysis	Determines the elements present in the sample	Defect analysis
TOF-SIMS 	Depth Profiling at Wide Mass Range	Depth Profile Analysis at >400 mass units	Defect analysis



**The NANOTECHNOLOGY
LABORATORY (NanoLab)
is the premier
nanotechnology research
facility in the Philippines.**



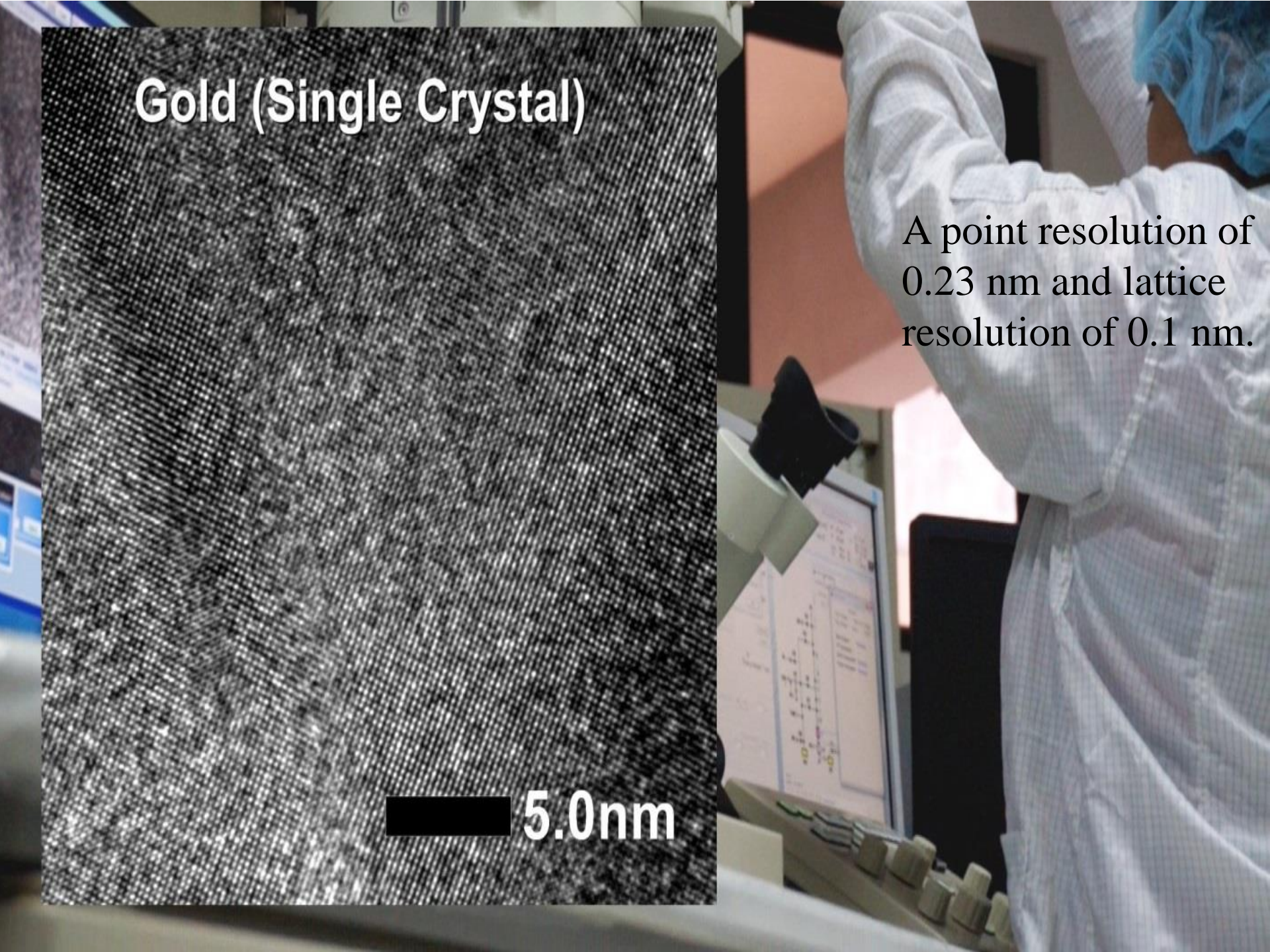
Field-Emission Transmission Electron Microscope

Can magnify materials up to 1.5 million times and is capable of rapid data acquisition.

Gold (Single Crystal)

5.0nm

A point resolution of 0.23 nm and lattice resolution of 0.1 nm.

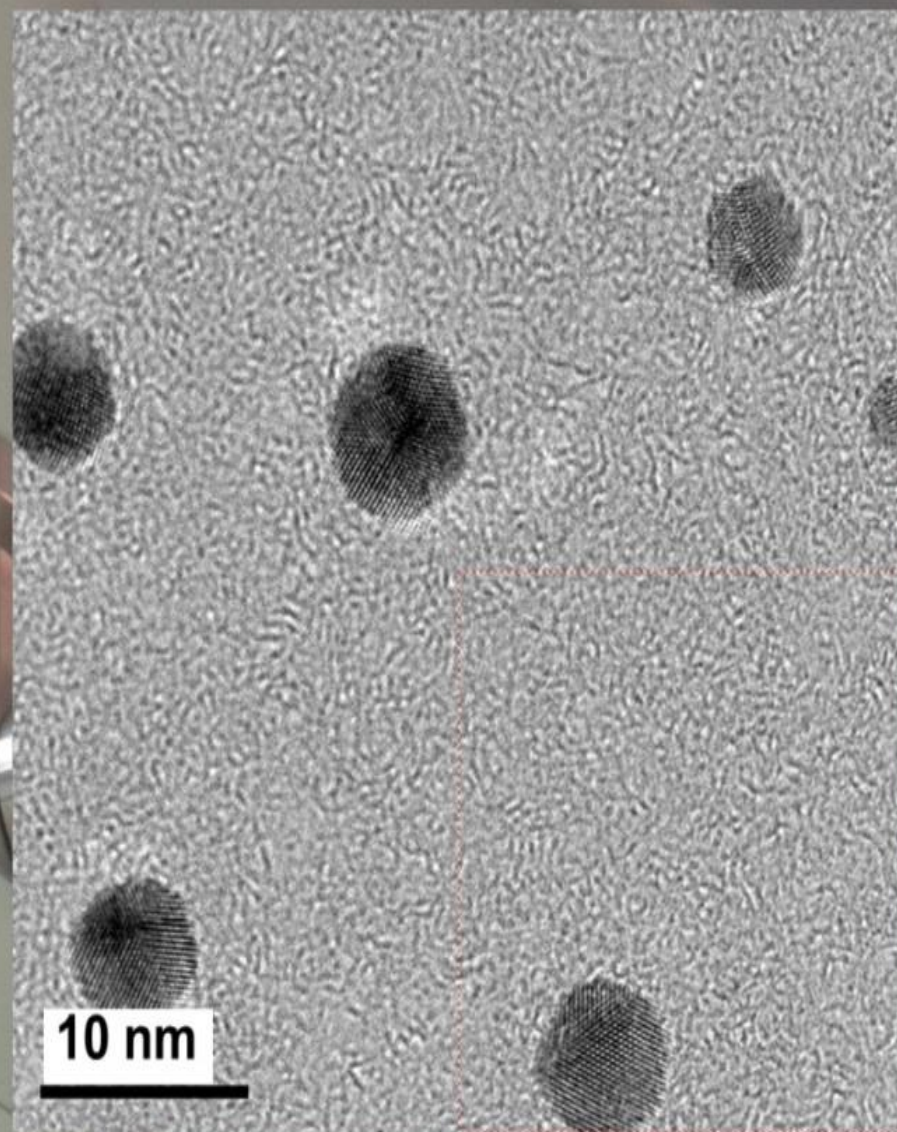
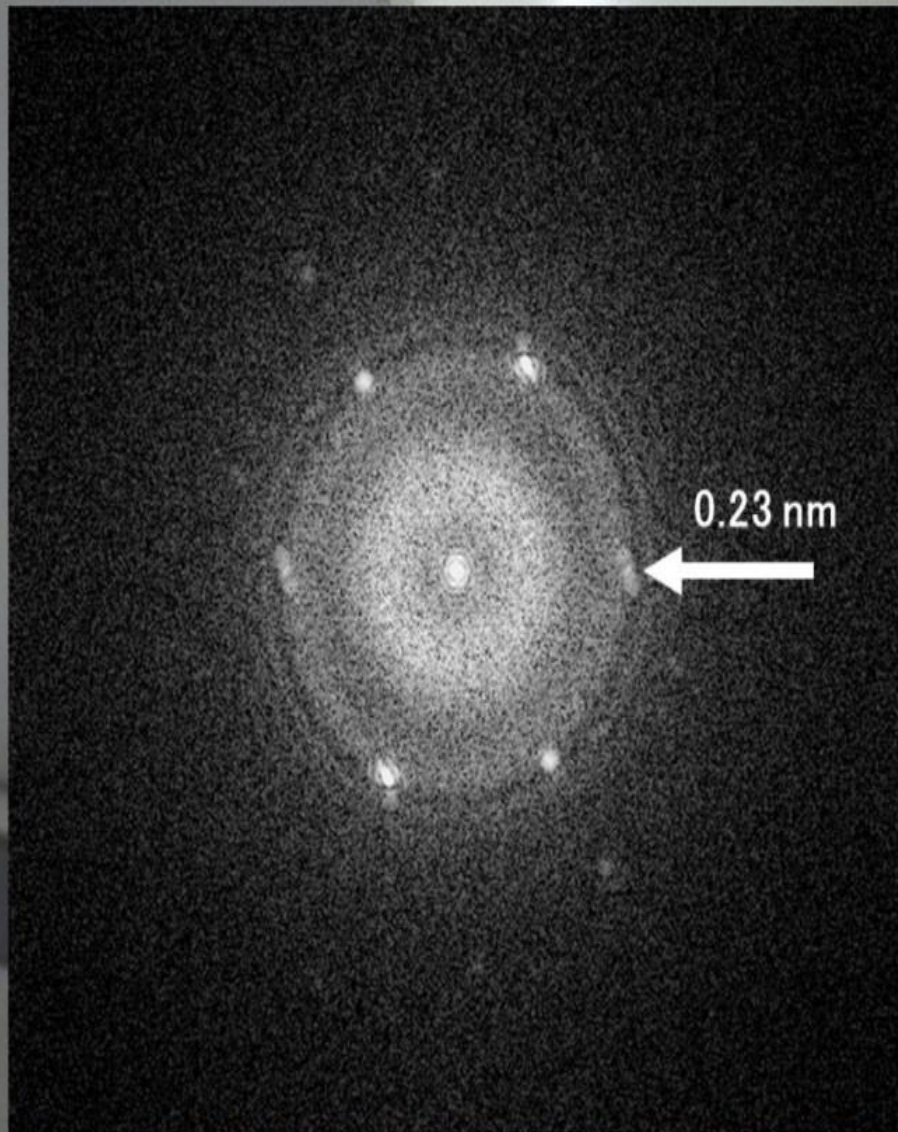


FE-TEM can perform secondary and back-scattered electron imaging.



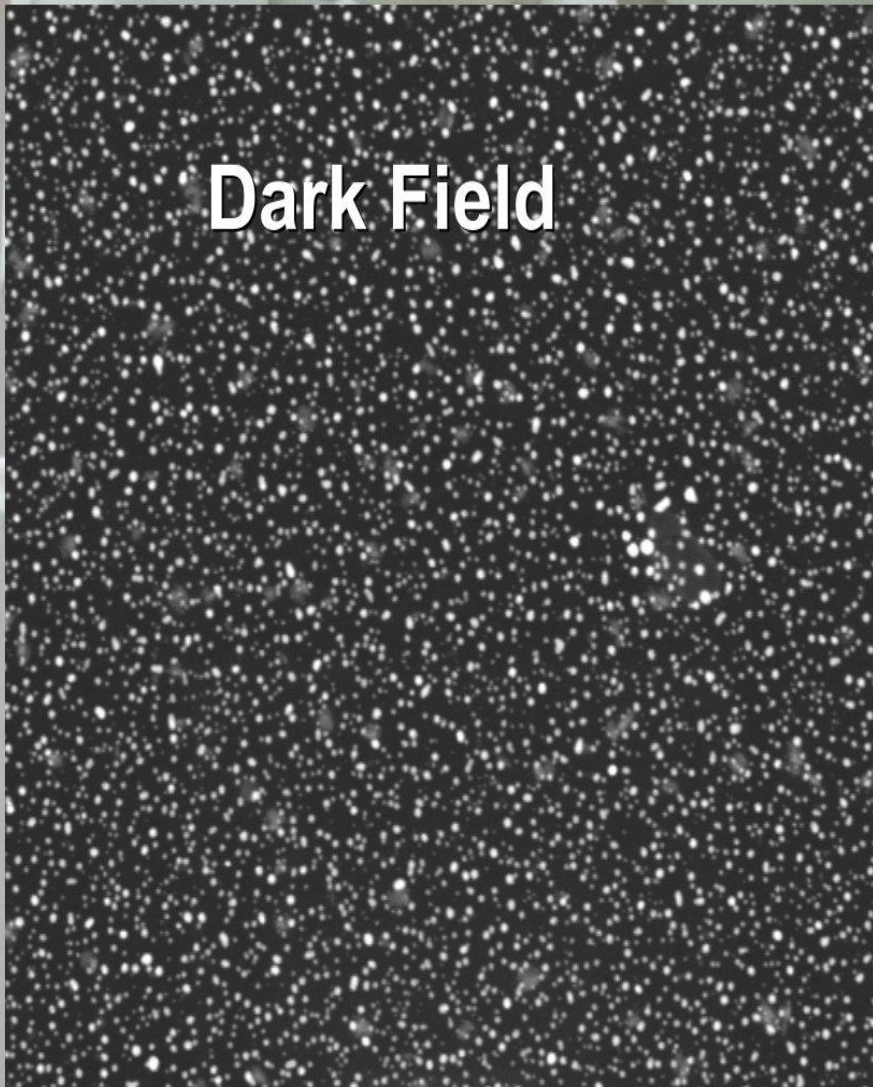
Gold Nano Particles

Selected Area Electron Diffraction Capability



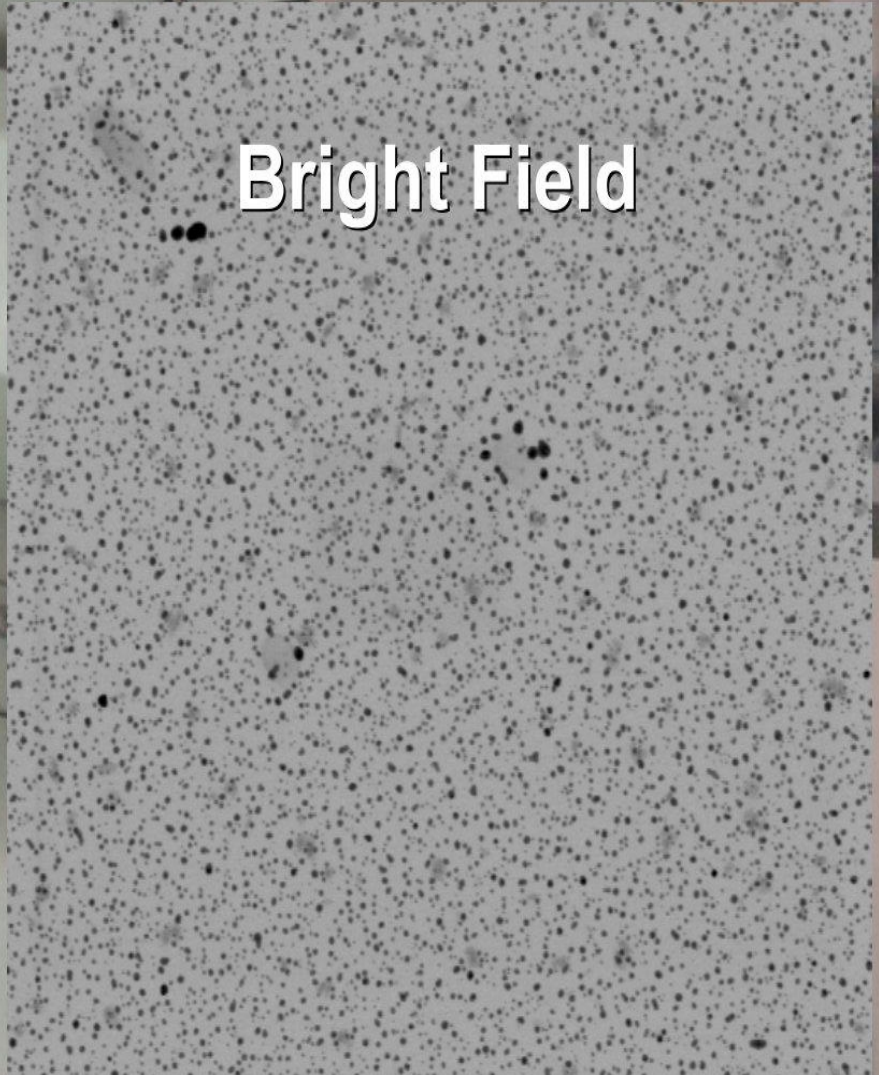
Gold Nano Particles

Dark Field



Specimen [STEM DF]
JEOL-TEM 200kV x250k 100%
Comment:
100.0nm
2/12/2014 09:32:12
Operator:

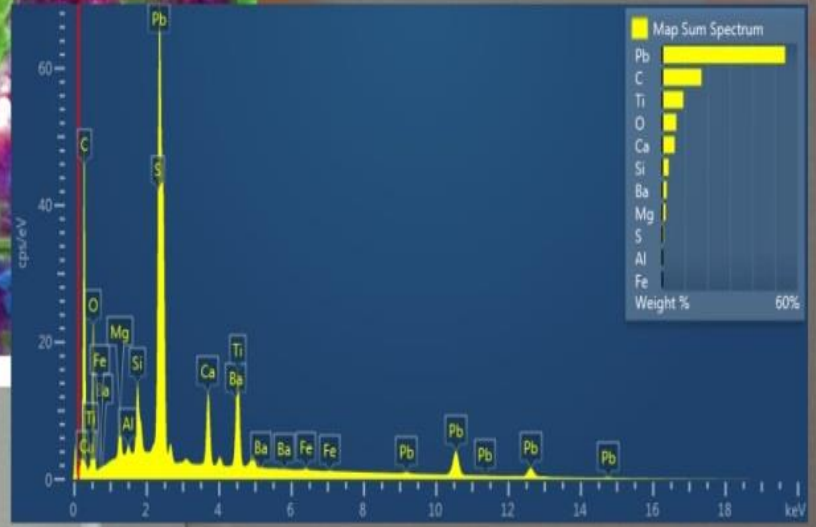
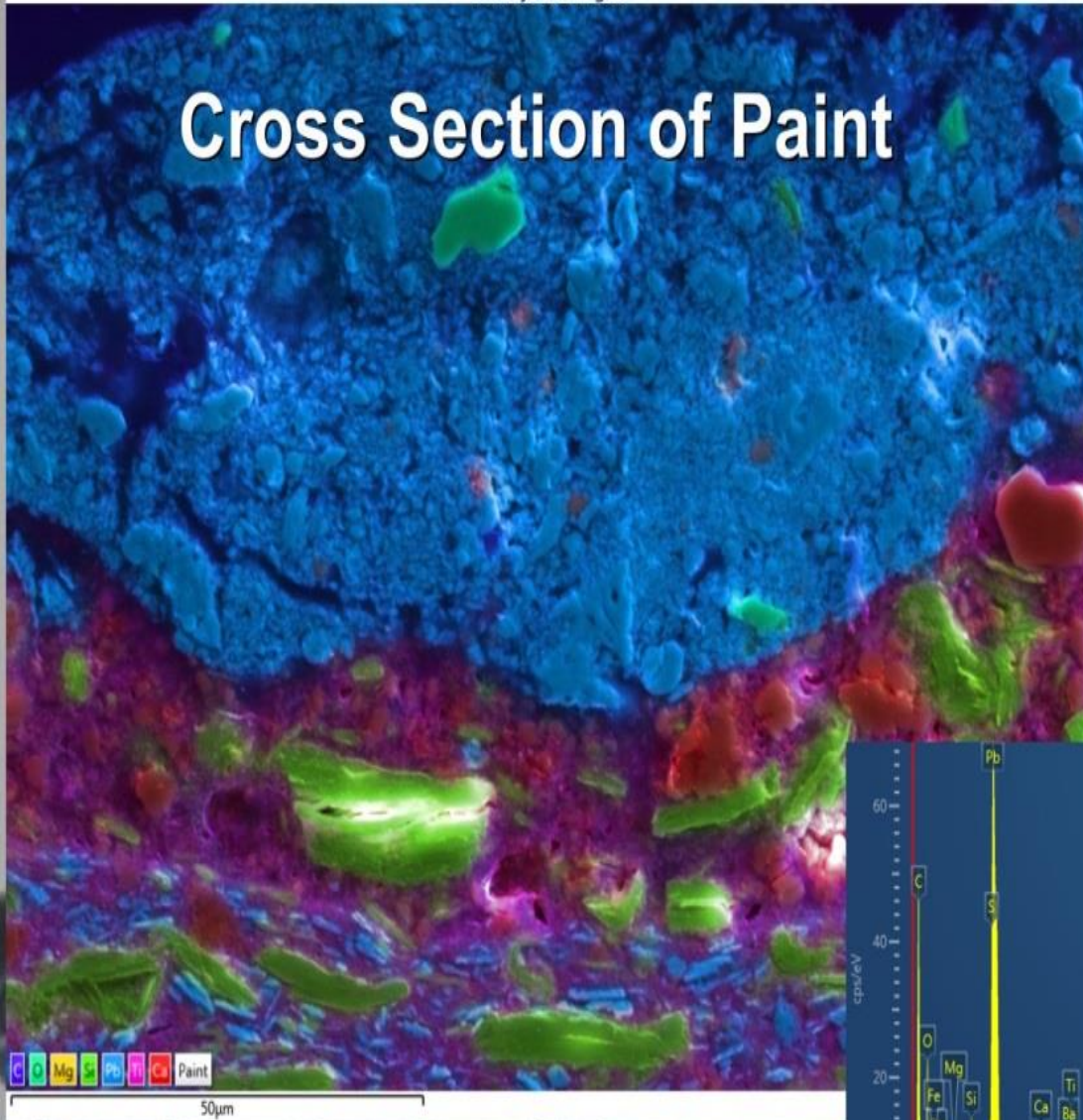
Bright Field



Specimen [STEM BF]
JEOL-TEM 200kV x200k 100%
Comment:
200.0nm
2/12/2014 09:36:32
Operator:

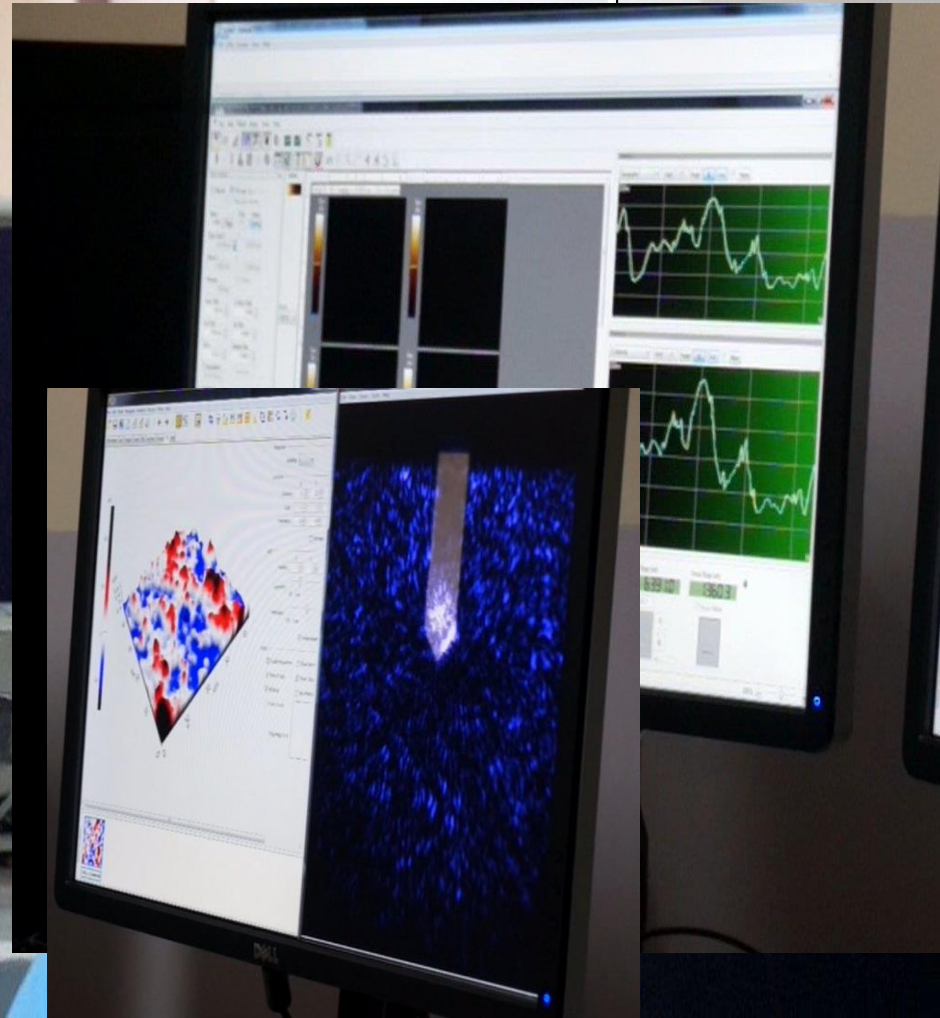
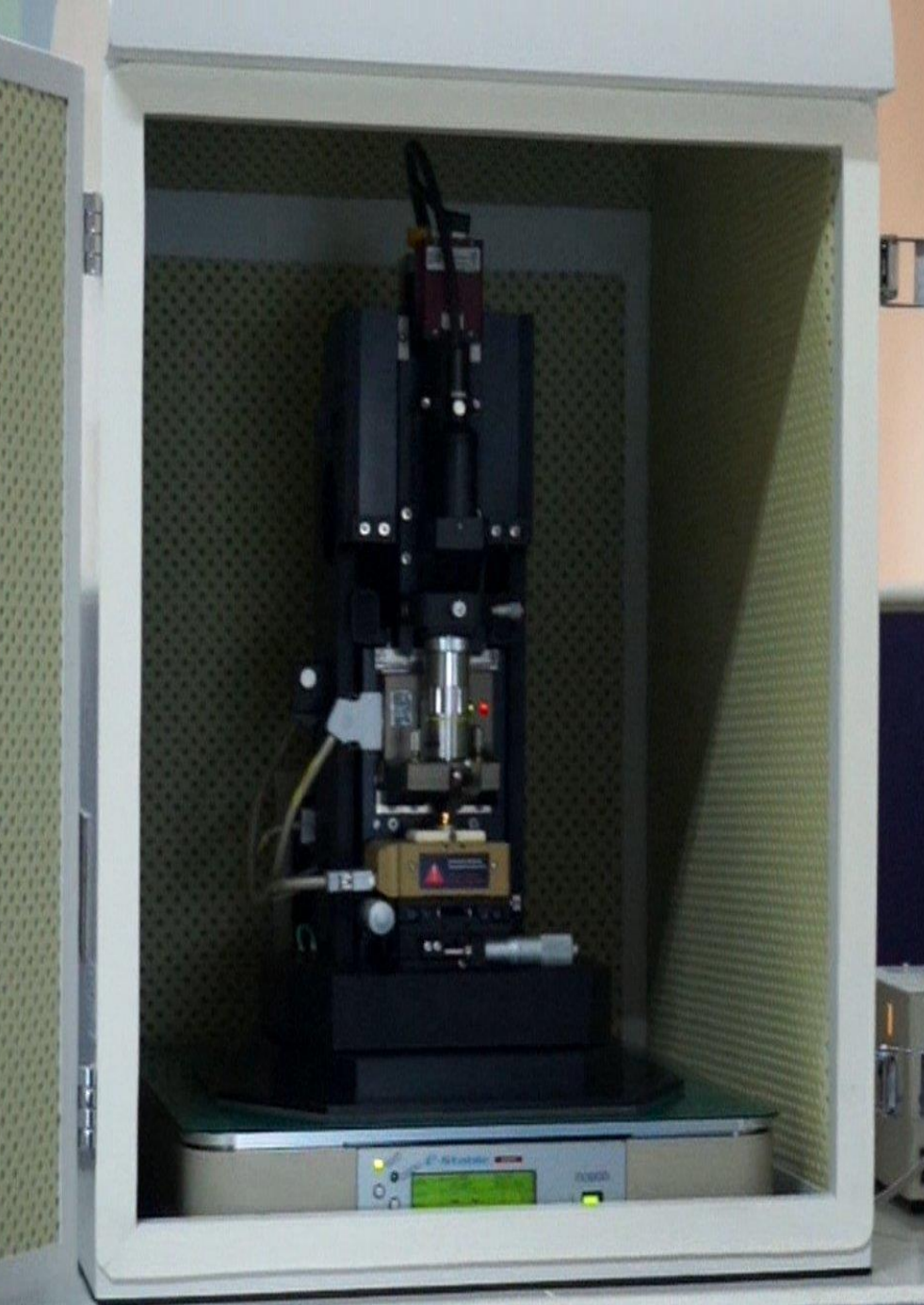
Gold Nano Particles

Cross Section of Paint



Energy Dispersive X-ray Spectrometer

Atomic Force Microscope



X-ray Diffractometer

LAMP

ON

OFF

O.L. (kW)

15 10 5

▲ 注意

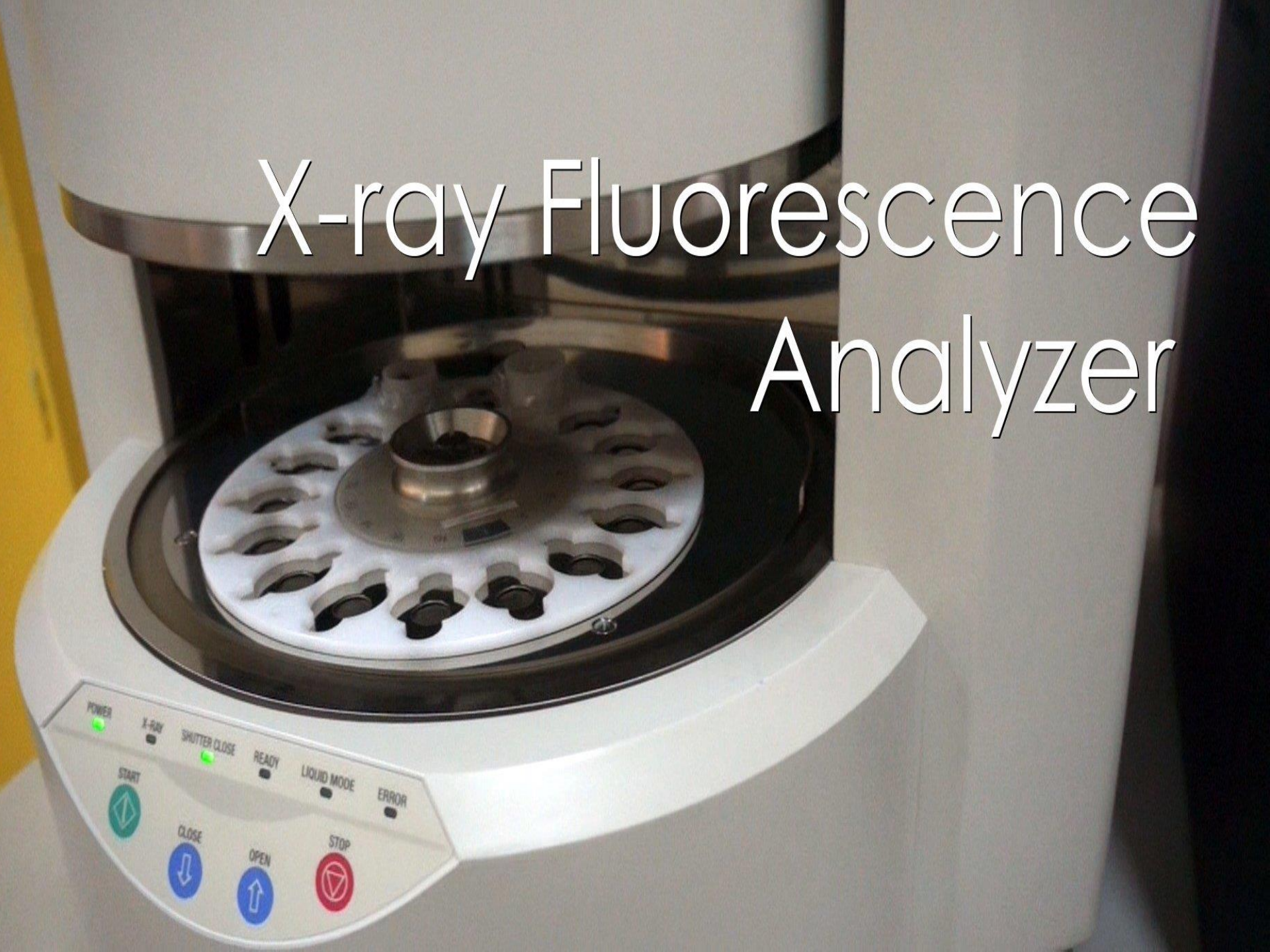
X線管の過熱防止のため、
X線管の電圧を調整してください。

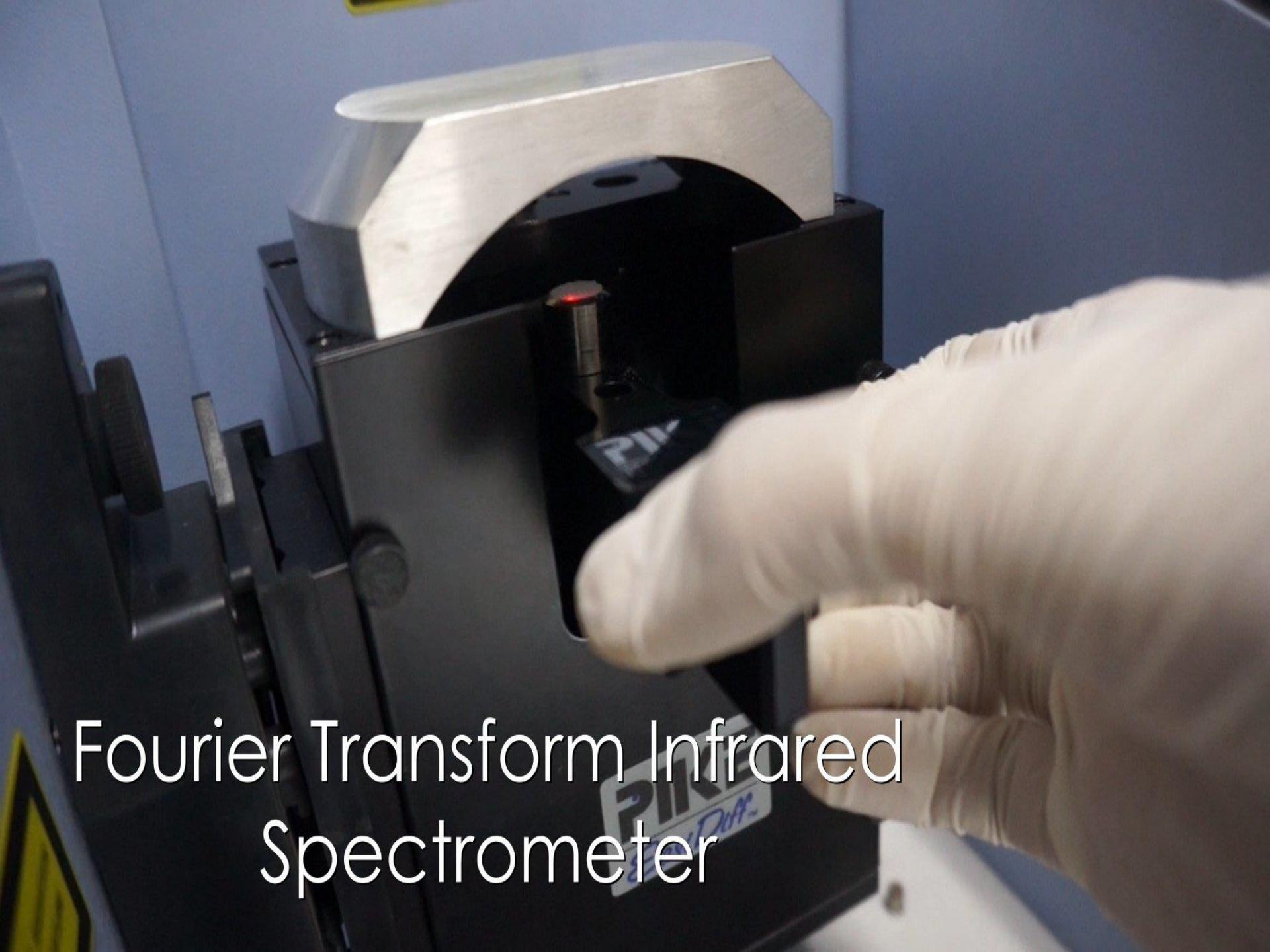
▲ NOTE

To avoid damage to an X-ray tube, set an appropriate value to an X-ray tube.

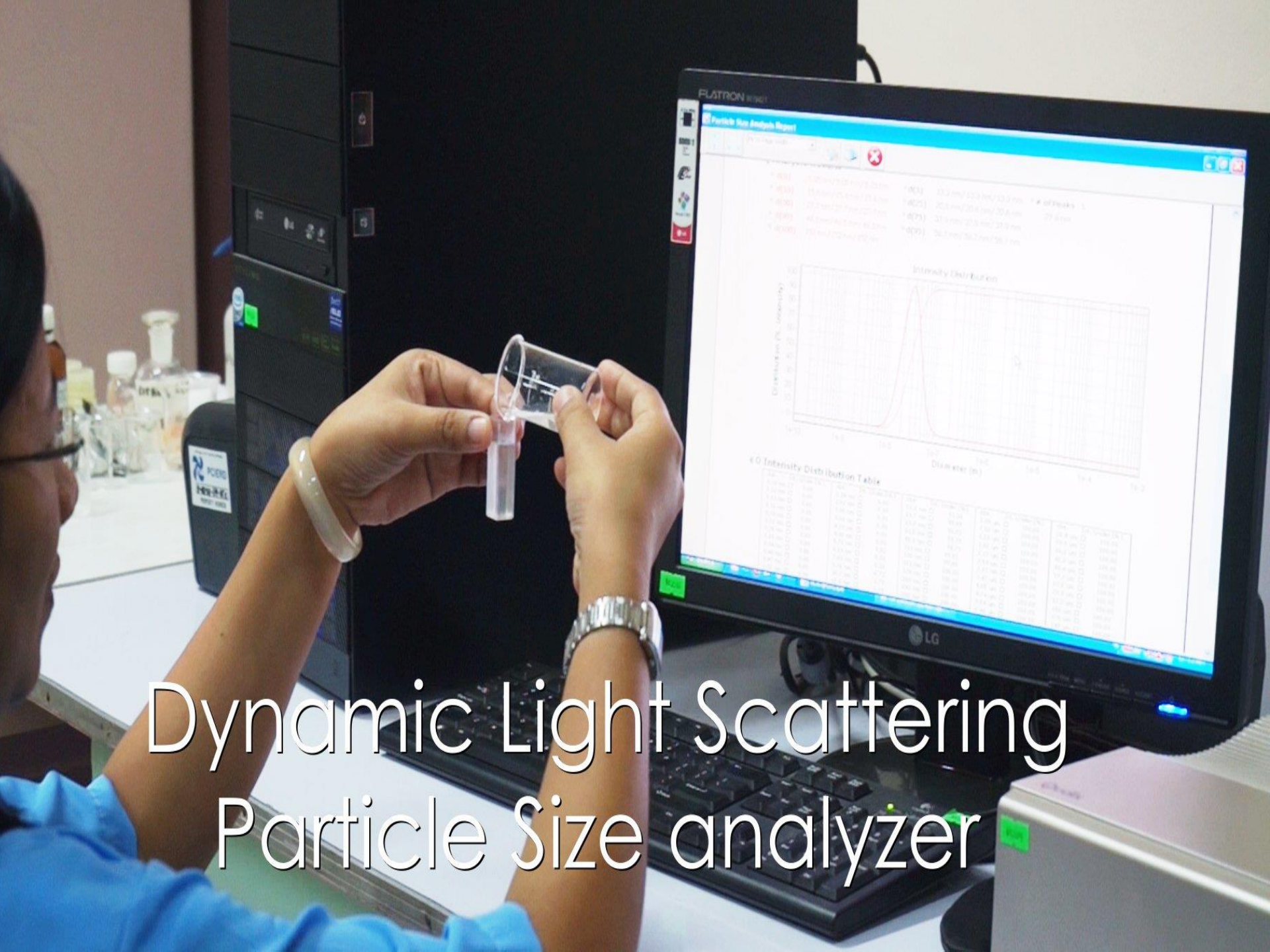


X-ray Fluorescence Analyzer





Fourier Transform Infrared Spectrometer



Dynamic Light Scattering Particle Size analyzer

A person wearing a light blue short-sleeved lab coat is shown in profile, facing right. They are holding a large, red, cylindrical container with a textured surface. The container is positioned in front of a large, dark-colored piece of laboratory equipment, which appears to be a Brunauer, Emmett and Teller (BET) surface area analyzer. In the background, there is a computer monitor on a desk displaying a software interface, and a printer on a shelf above it. The scene is set in a laboratory or office environment.

Brunauer, Emmett and
Teller Surface Area Analyzer

OPERATION UPDATE

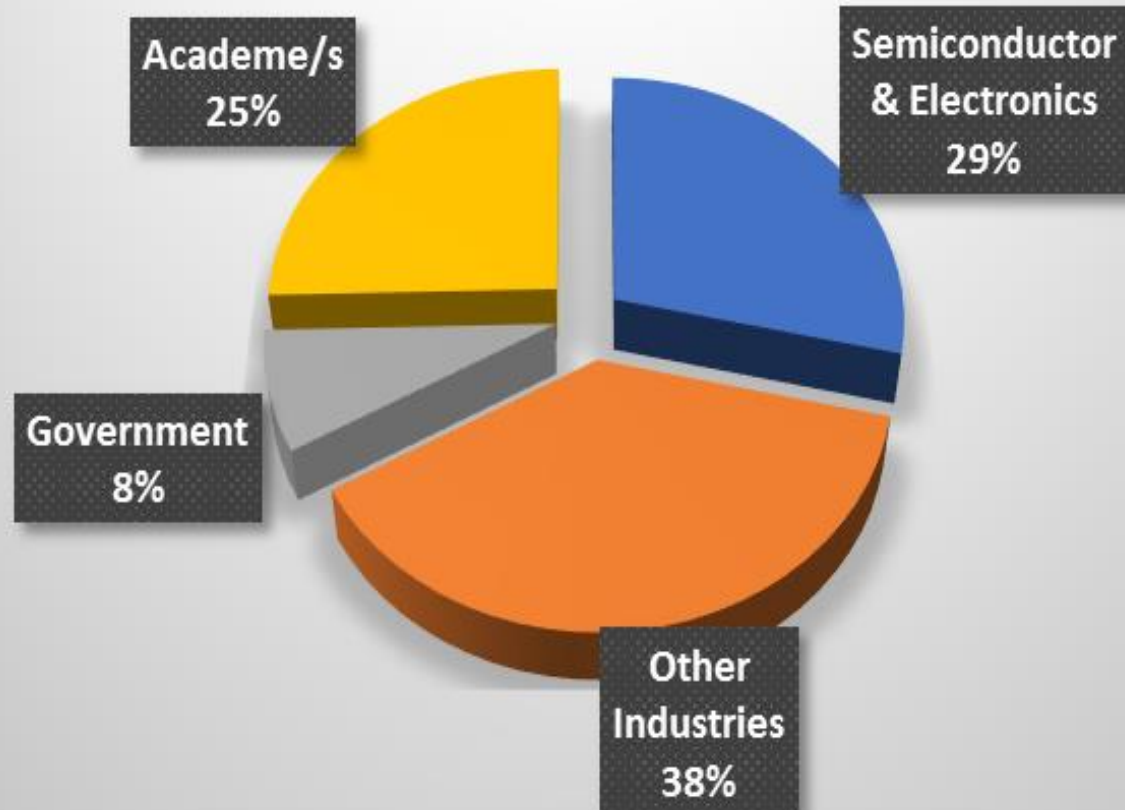
- Roll-out of **20% reduction** and **socialized rates (academe)** for testing services



CLIENTS

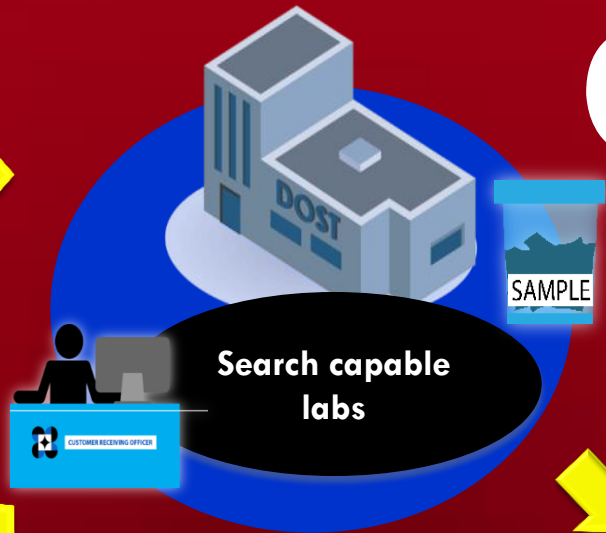
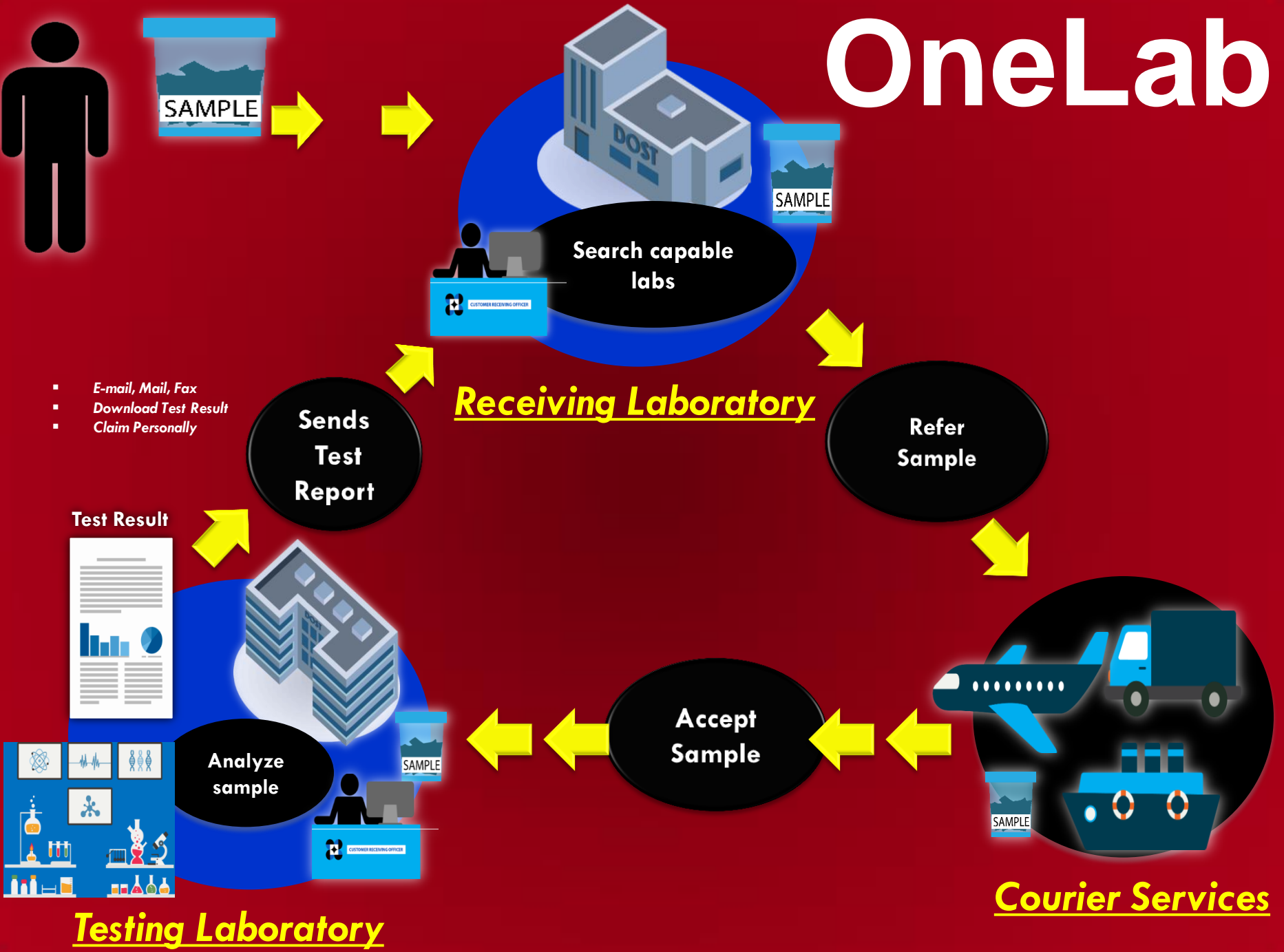


Breakdown of Clients in 2017



Objectives of test request: Quality Assurance, Materials Qualification, Reliability, Market Quality and Research

OneLab



Receiving Laboratory

Sends Test Report

Refer Sample



Accept Sample



Test Result



Analyze sample

Testing Laboratory

- E-mail, Mail, Fax
- Download Test Result
- Claim Personally

Courier Services

Come and visit us!

DOST-ITDI

Nano
Lab

Nanotechnology for every

Iran

